

Search Notes

Application/Control No.

10/524,177

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

VERMA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	410	4/4/2006	HN
	411		
	435.1		
	435.2		
	432.1		
	432.2		
	433		
	434		
	436		
	422.1		
Updated	search	8/25/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	4/4/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	8/25/2006	HN